## Moongon Jung

List of Publications by Year in descending order

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1684188 1872680 13 291 5 6 citations h-index g-index papers 13 13 13 261 docs citations times ranked citing authors all docs

#	Article	IF	CITATIONS
1	Fine-Grained 3-D IC Partitioning Study With a Multicore Processor. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2015, 5, 1393-1401.	2.5	4
2	Evaluating Chip-Level Impact of Cu/Low- <inline-formula> <tex-math notation="LaTeX">\$kappa \$ </tex-math></inline-formula> Performance Degradation on Circuit Performance at Future Technology Nodes. IEEE Transactions on Electron Devices, 2015, 62, 940-946.	3.0	12
3	Design and Analysis of 3D-MAPS (3D Massively Parallel Processor with Stacked Memory). IEEE Transactions on Computers, 2015, 64, 112-125.	3.4	52
4	TSV stress-aware full-chip mechanical reliability analysis and optimization for 3D IC. Communications of the ACM, 2014, 57, 107-115.	4.5	57
5	Impact of size effects in local interconnects for future technology nodes: A study based on full-chip layouts. , 2014, , .		23
6	Block-level designs of die-to-wafer bonded 3D ICs and their design quality tradeoffs. , 2013, , .		4
7	Chip/Package Mechanical Stress Impact on 3-D IC Reliability and Mobility Variations. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2013, 32, 1694-1707.	2.7	12
8	Chip/package co-analysis of thermo-mechanical stress and reliability in TSV-based 3D ICs. , 2012, , .		14
9	Design for manufacturability and reliability for TSV-based 3D ICs. , 2012, , .		24
10	TSV Stress-Aware Full-Chip Mechanical Reliability Analysis and Optimization for 3-D IC. IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, 2012, 31, 1194-1207.	2.7	44
11	A fast simulation framework for full-chip thermo-mechanical stress and reliability analysis of through-silicon-via based 3D ICs. , $2011,  ,  .$		11
12	A study of TSV variation impact on power supply noise. , 2011, , .		7
13	A study of IR-drop noise issues in 3D ICs with through-silicon-vias. , 2010, , .		27